Low Voltage Bias Stabilizer with Enable

MDC5001T1

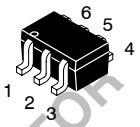
SILICON SMALLBLOCK™ INTEGRATED CIRCUIT

- Maintains Stable Bias Current in N−Type Discrete Bipolar Junction and Field Effect Transistors
- Provides Stable Bias Using a Single Component Without Use of Emitter Ballast and Bypass Components
- Operates Over a Wide Range of Supply Voltages Down to 1.8 Vdc
- Reduces Bias Current Variation Due to Temperature and Unit−to−Unit Parametric Changes
- Consumes $<$ 0.5 mW at V_{CC} = 2.75 V
- Active High Enable is CMOS Compatible

This device provides a reference voltage and acts as a DC feedback element around an external discrete, NPN BJT or N−Channel FET. It allows the external transistor to have its emitter/source directly grounded and still operate with a stable collector/drain DC current. It is primarily intended to stabilize the bias of discrete RF stages operating from a low voltage regulated supply, but can also be used to stabilize the bias current of any linear stage in order to eliminate emitter/source bypassing and achieve tighter bias regulation over temperature and unit variations. The "ENABLE" polarity nulls internal current, Enable current, and RF transistor current in "STANDBY." This device is intended to replace a circuit of three to six discrete components.

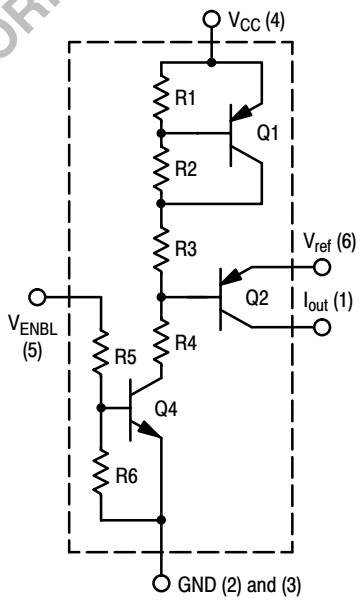
The combination of low supply voltage, low quiescent current drain, and small package make the MDC5001T1 ideal for portable communications applications such as:

- Cellular Telephones
- Pagers
- PCN/PCS Portables
- GPS Receivers
- PCMCIA RF Modems
- Cordless Phones
- Broadband and Multiband Transceivers and Other Portable Wireless Products



CASE 419B−01, Style 19
SOT−363

INTERNAL CIRCUIT DIAGRAM



February, 2005 − Rev. XXX
Publication Order Number:
MDC5001T1/D

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Power Supply Voltage	V_{CC}	15	Vdc
Ambient Operating Temperature Range	T_A	−40 to +85	°C
Storage Temperature Range	T_{stg}	−65 to +150	°C
Junction Temperature	T_J	150	°C
Collector Emitter Voltage (Q2)	V_{CEO}	−15	V
Enable Voltage (Pin 5)	V_{ENBL}	V_{CC}	V

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Total Device Power Dissipation (FR−5 PCB of 1″ × 0.75″ × 0.062″, T_A = 25°C) Derate above 25°C	P_D	 150 1.2	mW mW/°C
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	833	°C/W

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Recommended Operating Supply Voltage	V_{CC}	1.8	2.75	10	Volts
Power Supply Current (V_{CC} = 2.75 V) V_{ref}, I_{out} are unterminated See Figure 8	I_{CC}	—	130	200	μA
Q2 Collector Emitter Breakdown Voltage (I_{C2} = 10 μA, I_{B2} = 0)	$V_{(BR)CEO2}$	15			Volts
Reference Voltage (V_{ENBL} = V_{CC} = 2.75 V, V_{out} = 0.7 V) (I_{out} = 30 μA) (I_{out} = 150 μA) See Figure 1	V_{ref}	 2.050 2.110	 2.075 2.135	 2.100 2.160	Volts
Reference Voltage (V_{ENBL} = V_{CC} = 2.75 V, V_{out} = 0.7 V, −40°C ≤ T_A ≤ +85°C) V_{CC} Pulse Width = 10 mS, Duty Cycle = 1% (I_{out} = 10 μA) (I_{out} = 30 μA) (I_{out} = 100 μA) See Figures 2 and 11	ΔV_{ref}		 ±5.0 ±15 ±25	 ±10 ±30 ±50	mV

The following SPICE models are provided as a convenience to the user and every effort has been made to insure their accuracy. However, no responsibility for their accuracy is assumed by ON Semiconductor.

.MODEL Q4 NPN

BF = 136	NE = 1.6
BR = 0.2	NF = 1.005
CJC = 318.6 f	RB = 140
CJE = 569.2 f	RBM = 70
CJS = 1.9 p	RC = 180
EG = 1.215	RE = 1.6
FC = 0.5	TF = 553.6 p
IKF = 24.41 m	TR = 10 n
IKR = 0.25	VAF = 267.6
IRB = 0.0004	VAR = 12
IS = 256E−18	VJC = 0.4172
ISC = 1 f	VJE = 0.7245
ISE = 500E−18	VJS = 0.39
ITF = 0.9018	VTF = 10
MJC = 0.2161	XTB = 1.5
MJE = 0.3373	XTF = 2.077
MJS = 0.13	XTI = 3
NC = 1.09	

.MODEL Q1, Q2 PNP

BF = 87	NK = 0.5
BR = 0.6	NR = 1.0
CJC = 800E−15	RB = 720
CJE = 46E−15	RBM = 470
EG = 1.215	RC = 180
FC = 0.5	RE = 26
IKF = 3.8E−04	TF = 15E−9
IKR = 2.0	TR = 50E−09
IRB = 0.9E−3	VAF = 54.93
IS = 1.027E−15	VAR = 20
ISC = 10E−18	VAR = 20
ISE = 1.8E−15	VJC = 0.4172
ITF = 2E−3	VJE = 0.4172
MJC = 0.2161	VTF = 10
MJE = 0.2161	XTB = 1.5
NC = 0.8	XTF = 2.0
NE = 1.38	XTI = 3
NF = 1.015	

RESISTOR VALUES

R1 = 12 K
R2 = 6 K
R3 = 3.4 K
R4 = 12 K
R5 = 20 K
R6 = 40 K

These models can be retrieved electronically by accessing the ON Semiconductor Web page at http://design−net.sps.mot.com/models and searching the section on SMALLBLOCK™ models

TYPICAL OPEN LOOP CHARACTERISTICS

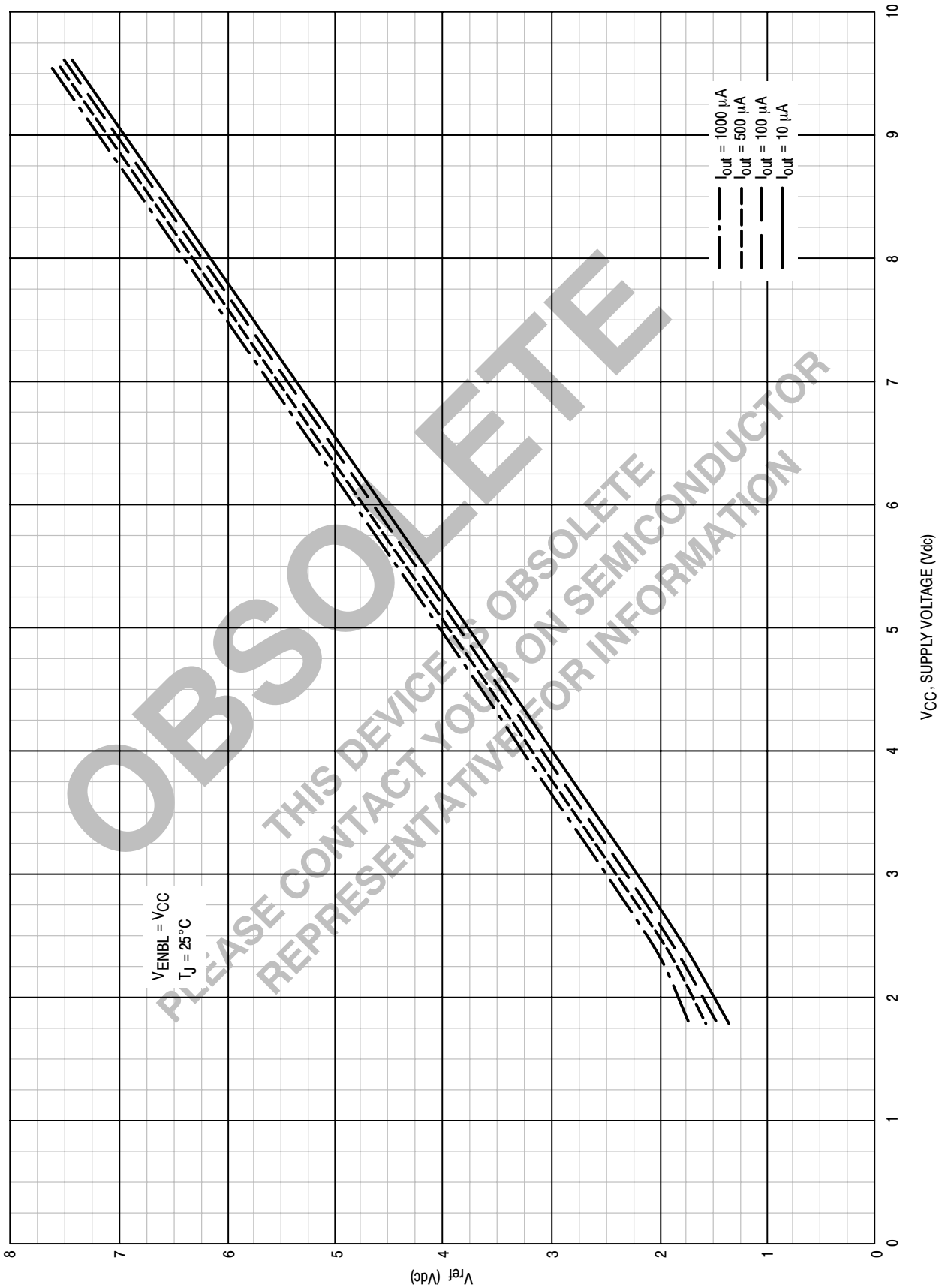


Figure 1. V_{ref} versus V_{CC} @ I_{out}

TYPICAL OPEN LOOP CHARACTERISTICS

(Refer to Circuits of Figures 10 through 15)

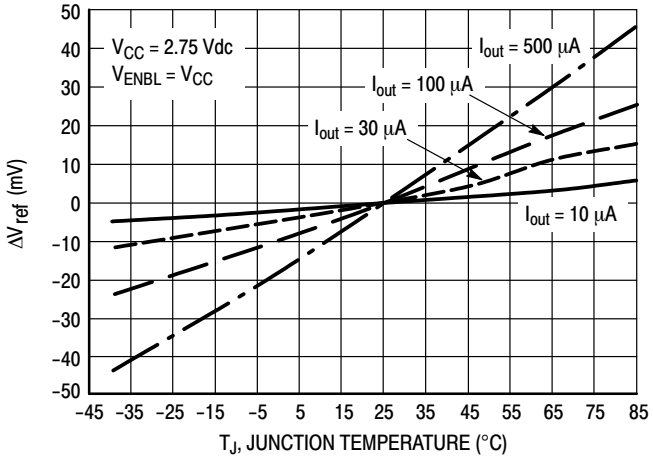


Figure 2. ΔV_{ref} versus T_J @ I_{out}

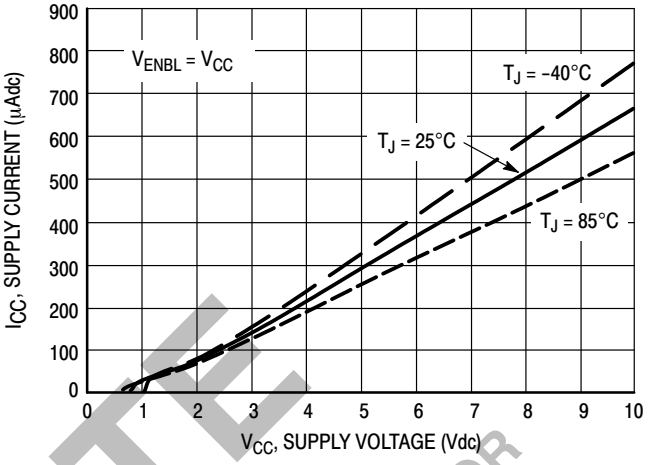


Figure 3. I_{CC} versus V_{CC} @ T_J

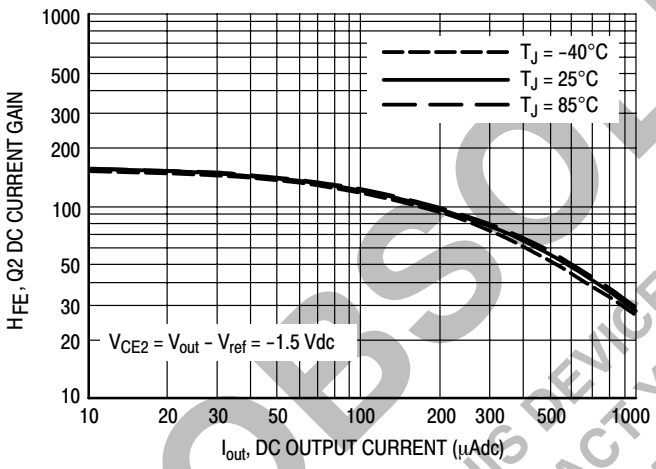


Figure 4. Q2 Current Gain versus Output Current @ T_J

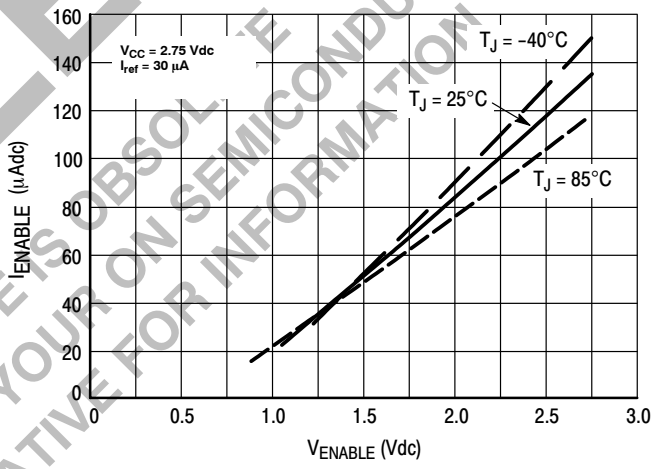


Figure 5. I_{enable} versus V_{enable}

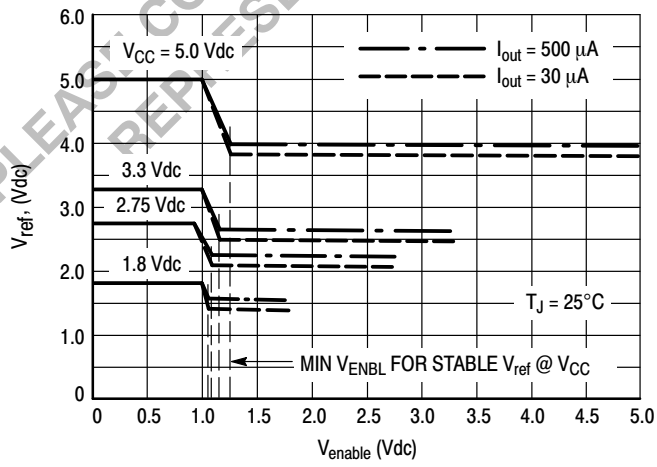


Figure 6. V_{ref} versus V_{enable} @ V_{CC} and I_{out}

TYPICAL CLOSED LOOP PERFORMANCE

(Refer to Circuits of Figures 16 & 17)

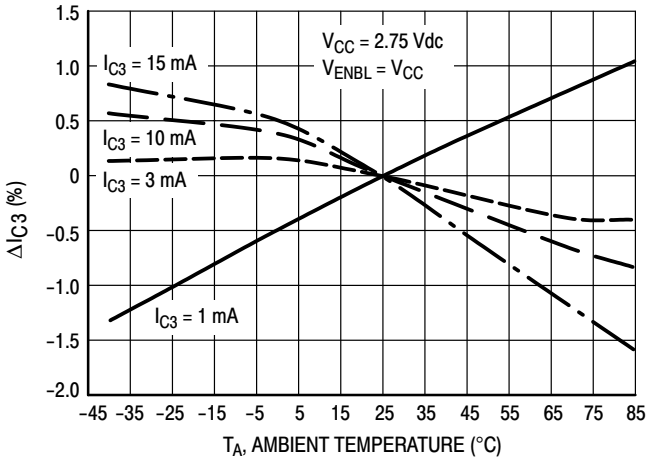


Figure 7. ΔI_{C3} versus T_A @ I_{C3}

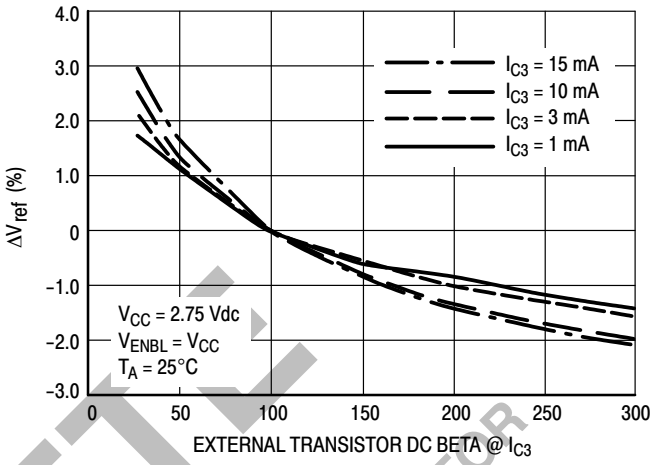


Figure 8. ΔV_{ref} versus External Transistor DC Beta @ I_{C3}

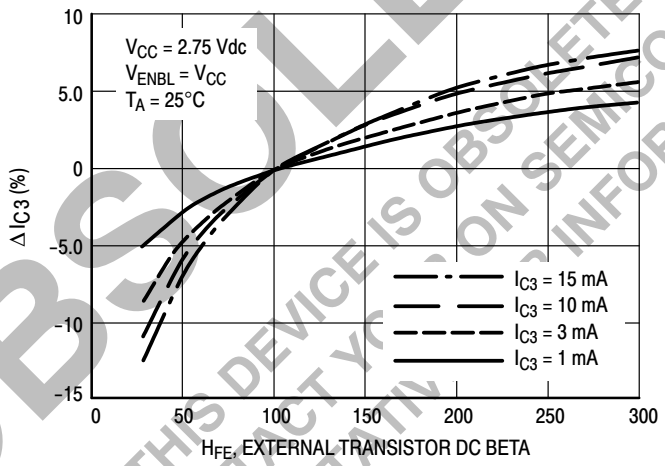


Figure 9. ΔI_{C3} versus External Transistor DC Beta @ I_{C3}

OPEN LOOP TEST CIRCUITS

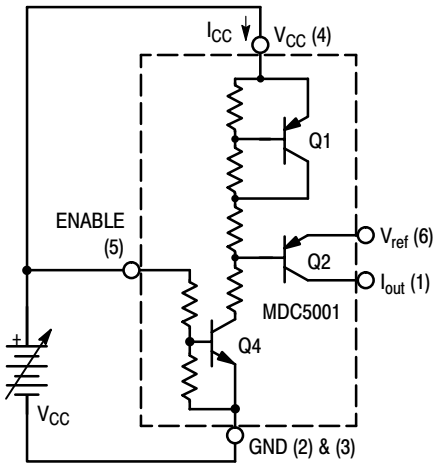


Figure 10. I_{CC} versus V_{CC} Test Circuit

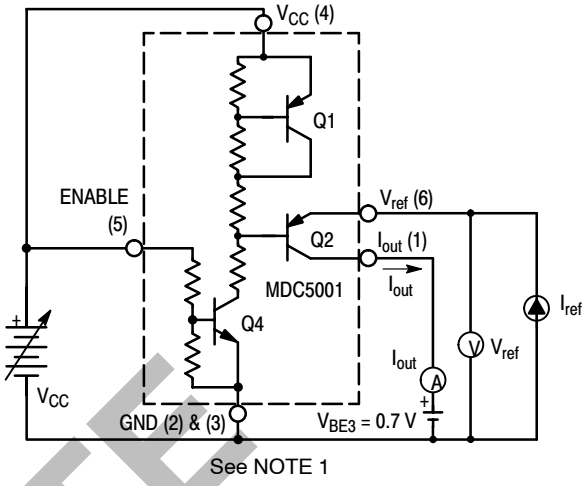


Figure 11. V_{ref} versus V_{CC} Test Circuit

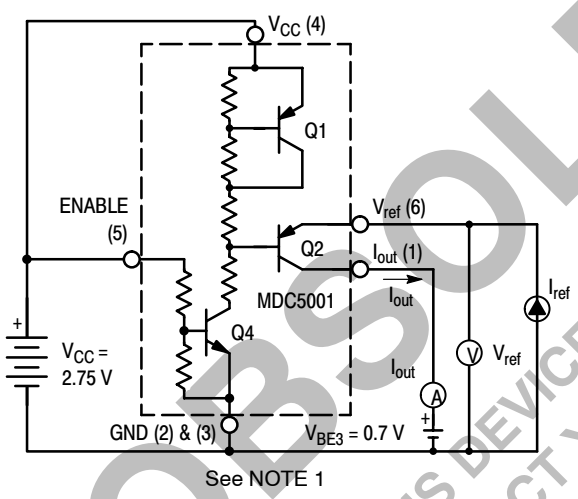


Figure 12. V_{ref} versus T_J Test Circuit

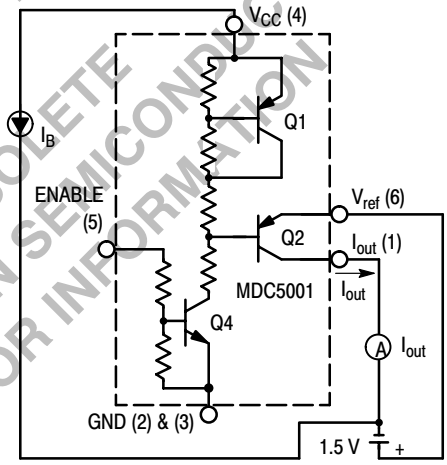


Figure 13. H_{FE} versus I_{out} Test Circuit

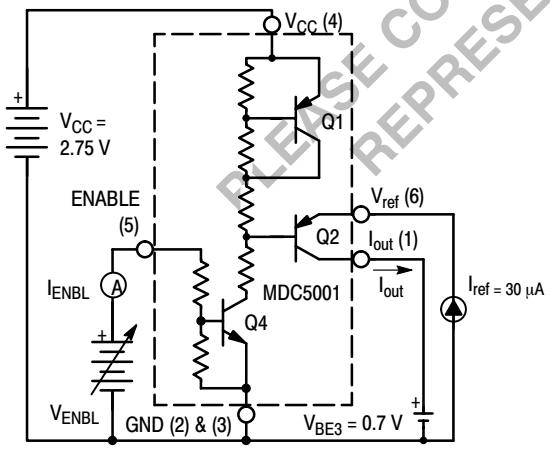


Figure 14. I_{ENBL} versus V_{ENBL} Test Circuit

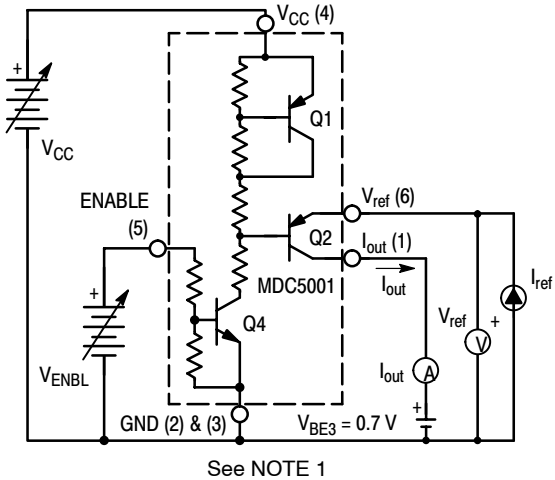


Figure 15. V_{ref} versus V_{ENBL} Test Circuit

NOTE 1: V_{BE3} is used to simulate actual operating conditions that reduce V_{CE2} & H_{FE2}, and increase I_{B2} & V_{ref}.

CLOSED LOOP TEST CIRCUITS

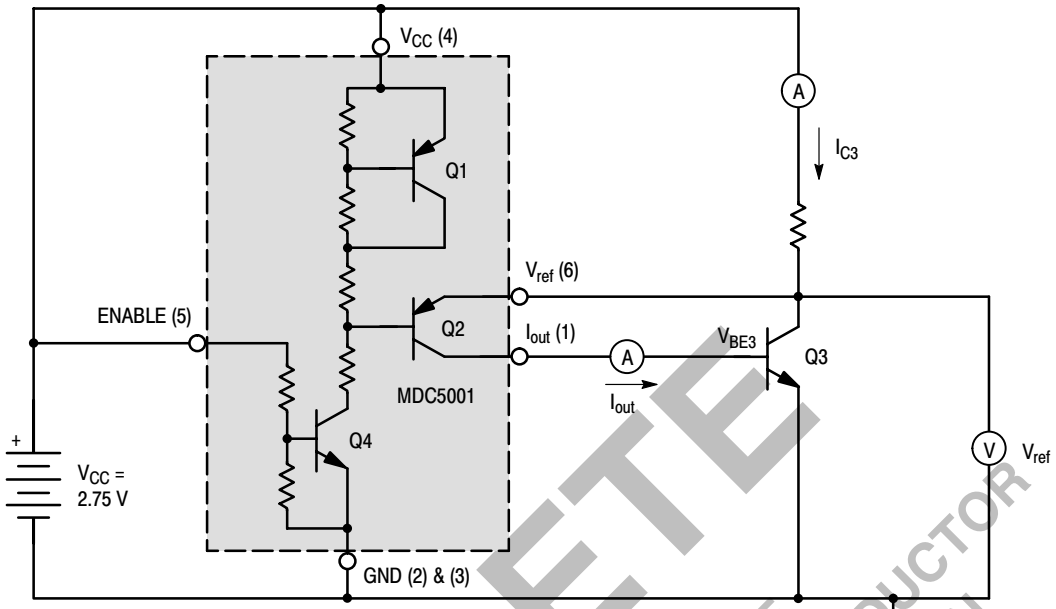
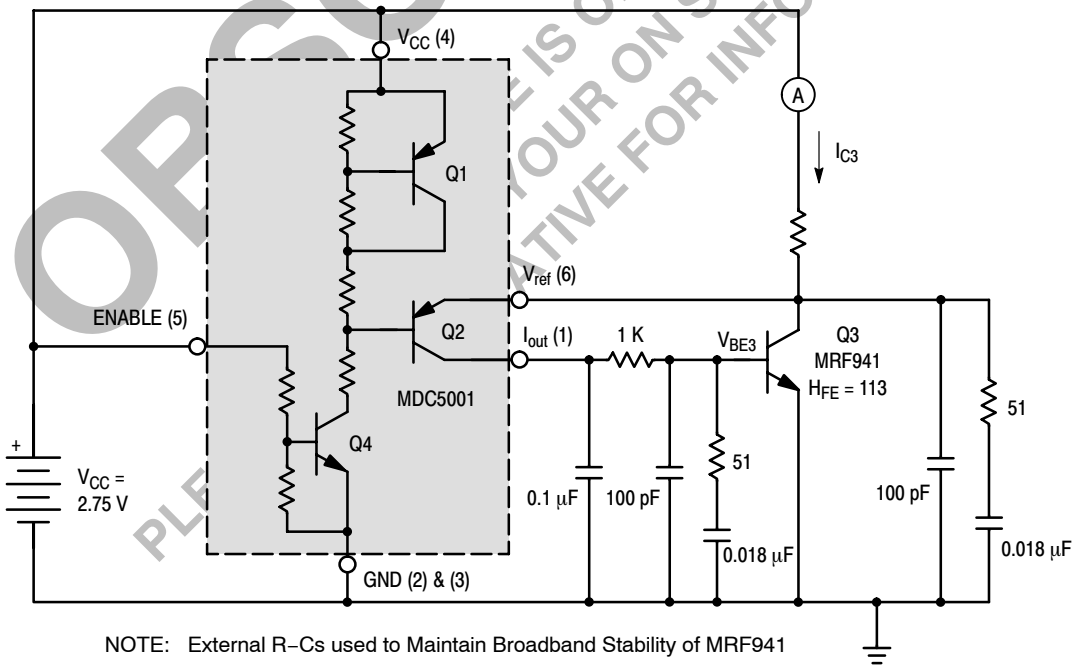


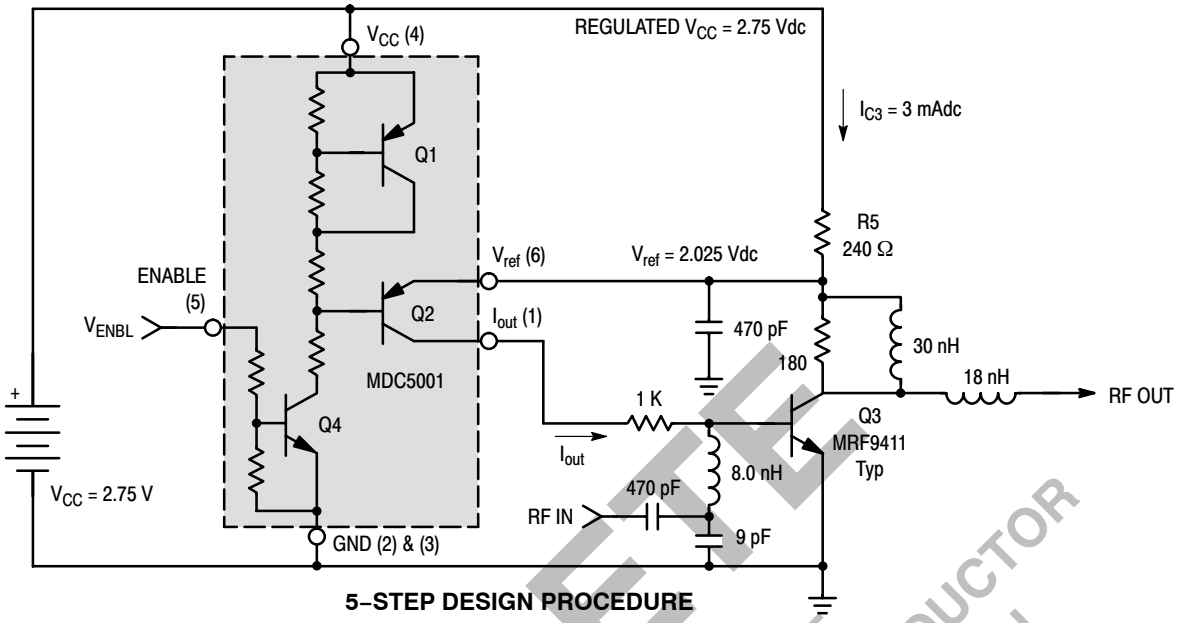
Figure 16. V_{ref} and RF Stage I_{C3} versus H_{FE3} Test Circuit



NOTE: External R−Cs used to Maintain Broadband Stability of MRF941

Figure 17. RF Stage I_{C3} versus T_A Test Circuit

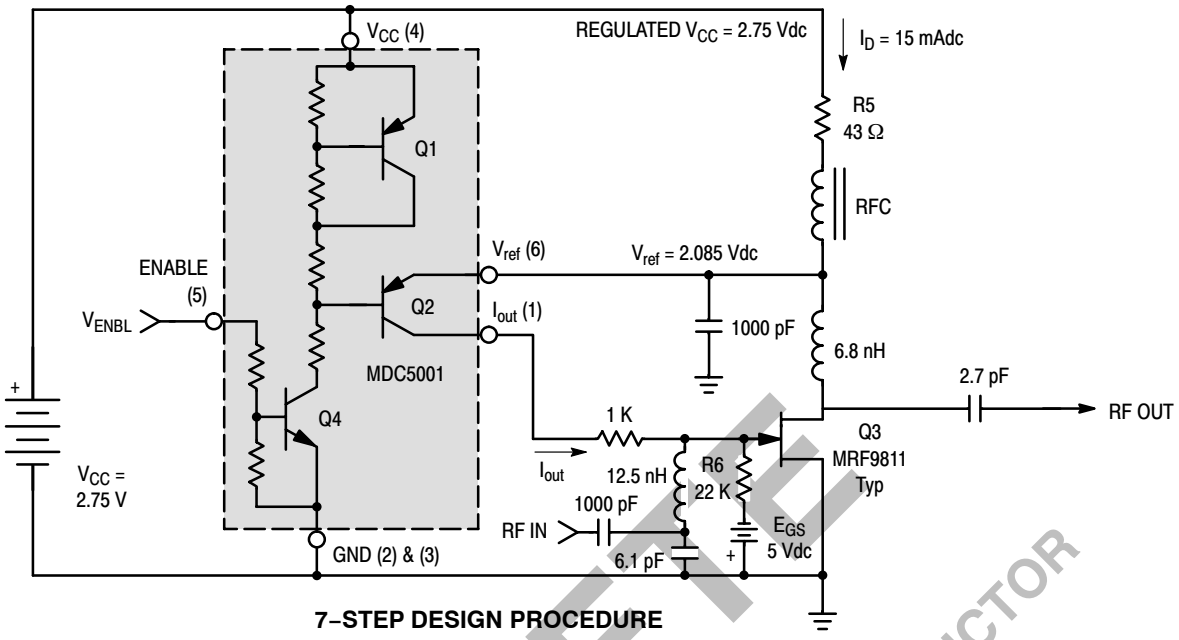
APPLICATION CIRCUITS



5−STEP DESIGN PROCEDURE

Step 1: Choose V_{CC} (1.8 V Min to 10 V Max)
Step 2: Insure that Min V_{ENBL} is ≥ minimum indicated in Figures 5 and 6.
Step 3: Choose bias current, I_{C3}, and calculate needed I_{out} from typ H_{FE3}
Step 4: From Figure 1, read V_{ref} for V_{CC} and I_{out} calculated.
Step 5: Calculate Nominal R5 = $(V_{CC} - V_{ref}) \div (I_{C3} + I_{out})$. Tweak as desired.

Figure 18. Class A Biasing of a Typical 900 MHz BJT Amplifier Application



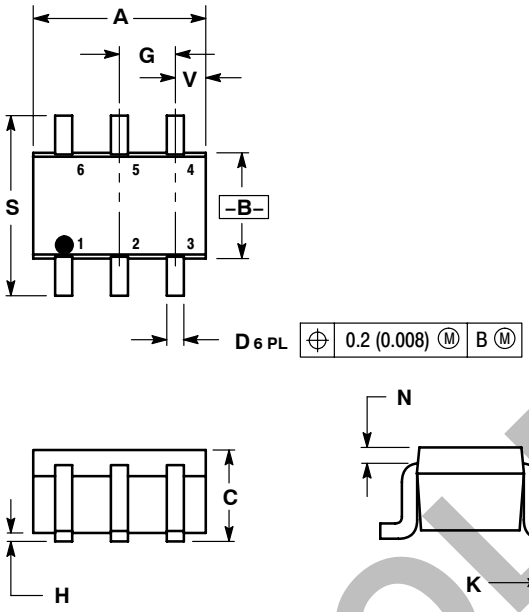
7–STEP DESIGN PROCEDURE

Step 1: Choose V_{CC} (1.8 V Min to 10 V Max)
Step 2: Insure that Min V_{ENBL} is ≥ minimum indicated in Figures 5 and 6.
Step 3: Choose bias current, I_D, and determine needed gate–source voltage, V_{GS}.
Step 4: Choose I_{out} keeping in mind that too large an I_{out} can impair MDC5000 $\Delta V_{ref}/\Delta T_J$ performance (Figure 2) but too large an R6 can cause I_{DGO} & I_{GSO} to bias on the FET.
Step 5: Calculate R6 = $(V_{GS} + E_{GS}) \div I_{out}$
Step 6: From Figure 1, read V_{ref} for V_{CC} & I_{out} chosen
Step 7: Calculate Nominal R5 = $(V_{CC} - V_{ref}) \div (I_D + I_{out})$. Tweak as desired.

Figure 19. Class A Biasing of a Typical 890 MHz Depletion Mode GaAs FET Amplifier

PACKAGE DIMENSIONS

SC−88 (SOT−363)
CASE 419B−01
ISSUE G



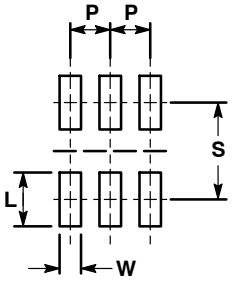
NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.071	0.087	1.80	2.20
B	0.045	0.053	1.15	1.35
C	0.031	0.043	0.80	1.10
D	0.004	0.012	0.10	0.30
G	0.026 BSC		0.65 BSC	
H	---	0.004	---	0.10
J	0.004	0.010	0.10	0.25
K	0.004	0.012	0.10	0.30
N	0.008 REF		0.20 REF	
S	0.079	0.087	2.00	2.20
V	0.012	0.016	0.30	0.40

STYLE 19:
PIN 1. I OUT
2. GND
3. GND
4. V CC
5. V EN
6. V REF

MDC5001T1

PACKAGE DIMENSIONS



DIM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
L	0.035		0.9	
P	0.026 BSC		0.65 BSC	
S	0.063 NOM		1.6 NOM	
W	0.014 NOM		0.34 NOM	

STYLE 19:
PIN 1. I OUT
2. GND
3. GND
4. V CC
5. V EN
6. V REF

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